

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/685,482	OHTANI ET AL.	
Examiner	Art Unit	
Ouoc A Tran	2176	

SEARCHED					
Subclass	Date	Examiner			
517	3/12/2006				
217	3/12/2006	4			
702	3/12/2006				
730	3/12/2006				
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	517 217 702	Subclass Date 517 3/12/2006 217 3/12/2006 702 3/12/2006			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Inventor Search (Double Patent)	3/12/2006	9
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB, USOCR) (see search history printout)	3/12/2006	H
ACM DataBase(see search history printout)	03/12/2006	8